

International **IR** Rectifier

PD - 96111

IRF7379QPbF

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dual N and P Channel MOSFET
- Surface Mount
- Available in Tape & Reel
- 150°C Operating Temperature
- Automotive [Q101] Qualified
- Lead-Free

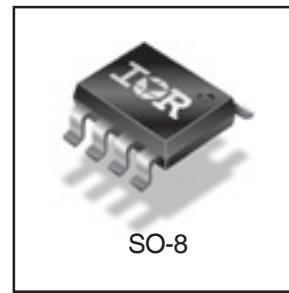
	N-Ch	P-Ch
V _{DSS}	30V	-30V
R _{DS(on)}	0.045Ω	0.090Ω

Top View

Description

Specifically designed for Automotive applications, these HEXFET® Power MOSFET's in a Dual SO-8 package utilize the lastest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of these Automotive qualified HEXFET Power MOSFET's are a 150°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These benefits combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.

The efficient SO-8 package provides enhanced thermal characteristics and dual MOSFET die capability making it ideal in a variety of power applications. This dual, surface mount SO-8 can dramatically reduce board space and is also available in Tape & Reel.



Absolute Maximum Ratings

	Parameter	Max.		Units
		N-Channel	P-Channel	
V _{SD}	Drain-to-Source Voltage	30	-30	
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V	5.8	-4.3	A
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 10V	4.6	-3.4	
I _{DM}	Pulsed Drain Current ①	46	-34	
P _D @ T _A = 25°C	Power Dissipation	2.5		
	Linear Derating Factor	0.02		W/°C
V _{GS}	Gate-to-Source Voltage	± 20		V
dV/dt	Peak Diode Recovery dV/dt ②	5.0	-5.0	V/ns
T _J , T _{STG}	Junction and Storage Temperature Range	-55 to + 150		°C

Thermal Resistance Ratings

	Parameter	Max.	Units
R _{θJA}	Maximum Junction-to-Ambient ③	50	°C/W

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Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter		Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	N-Ch	30	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
		P-Ch	-30	—	—		$V_{GS} = 0V, I_D = -250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	N-Ch	—	0.032	—	$\text{V}/^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
		P-Ch	—	-0.037	—		Reference to $25^\circ\text{C}, I_D = -1\text{mA}$
$R_{DS(\text{ON})}$	Static Drain-to-Source On-Resistance	N-Ch	—	0.038	0.045	Ω	$V_{GS} = 10V, I_D = 5.8\text{A}$ ③
		—	—	0.055	0.075		$V_{GS} = 4.5V, I_D = 4.9\text{A}$ ③
$R_{DS(\text{ON})}$	Static Drain-to-Source On-Resistance	P-Ch	—	0.070	0.090		$V_{GS} = -10V, I_D = -4.3\text{A}$ ③
		—	—	0.130	0.180		$V_{GS} = -4.5V, I_D = -3.7\text{A}$ ③
$V_{GS(\text{th})}$	Gate Threshold Voltage	N-Ch	1.0	—	—	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
		P-Ch	-1.0	—	—		$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$
g_f	Forward Transconductance	N-Ch	5.2	—	—	S	$V_{DS} = 15V, I_D = 2.4\text{A}$ ③
		P-Ch	2.5	—	—		$V_{DS} = -24V, I_D = -1.8\text{A}$ ③
I_{DSS}	Drain-to-Source Leakage Current	N-Ch	—	—	1.0	μA	$V_{DS} = 24\text{ V}, V_{GS} = 0\text{V}$
		P-Ch	—	—	-1.0		$V_{DS} = -24\text{V}, V_{GS} = 0\text{V}$
I_{DSS}	Drain-to-Source Leakage Current	N-Ch	—	—	25		$V_{DS} = 24\text{ V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
		P-Ch	—	—	-25		$V_{DS} = -24\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	N-P	—	—	± 100		$V_{GS} = \pm 20\text{V}$
Q_g	Total Gate Charge	N-Ch	—	—	25	nC	N-Channel
		P-Ch	—	—	25		$I_D = 2.4\text{A}, V_{DS} = 24\text{V}, V_{GS} = 10\text{V}$ ③
Q_{gs}	Gate-to-Source Charge	N-Ch	—	—	2.9		P-Channel
		P-Ch	—	—	2.9		$I_D = -1.8\text{A}, V_{DS} = -24\text{V}, V_{GS} = -10\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	N-Ch	—	—	7.9		
		P-Ch	—	—	9.0		
$t_{d(on)}$	Turn-On Delay Time	N-Ch	—	6.8	—	ns	N-Channel
		P-Ch	—	11	—		$V_{DD} = 15\text{V}, I_D = 2.4\text{A}, R_G = 6.0\Omega, R_D = 6.2\Omega$ ③
t_r	Rise Time	N-Ch	—	21	—		
		P-Ch	—	17	—		
$t_{d(off)}$	Turn-Off Delay Time	N-Ch	—	22	—	ns	P-Channel
		P-Ch	—	25	—		$V_{DD} = -15\text{V}, I_D = -1.8\text{A}, R_G = 6.0\Omega, R_D = 8.2\Omega$ ③
t_f	Fall Time	N-Ch	—	7.7	—		
		P-Ch	—	18	—		
L_D	Internal Drain Inductance	N-P	—	4.0	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L_S	Internal Source Inductance	N-P	—	6.0	—		
C_{iss}	Input Capacitance	N-Ch	—	520	—	pF	N-Channel
		P-Ch	—	440	—		$V_{GS} = 0\text{V}, V_{DS} = 25\text{V}, f = 1.0\text{MHz}$ ③
C_{oss}	Output Capacitance	N-Ch	—	180	—		P-Channel
		P-Ch	—	200	—		$V_{GS} = 0\text{V}, V_{DS} = -25\text{V}, f = 1.0\text{MHz}$ ③
C_{rss}	Reverse Transfer Capacitance	N-Ch	—	72	—		
		P-Ch	—	93	—		

Source-Drain Ratings and Characteristics

	Parameter		Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	N-Ch	—	—	3.1	A	
		P-Ch	—	—	-3.1		
I_{SM}	Pulsed Source Current (Body Diode) ①	N-Ch	—	—	46		
		P-Ch	—	—	-34		
V_{SD}	Diode Forward Voltage	N-Ch	—	—	1.0	V	$T_J = 25^\circ\text{C}, I_S = 1.8\text{A}, V_{GS} = 0\text{V}$ ③
		P-Ch	—	—	-1.0		$T_J = 25^\circ\text{C}, I_S = -1.8\text{A}, V_{GS} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	N-Ch	—	47	71	ns	N-Channel
		P-Ch	—	53	80		$T_J = 25^\circ\text{C}, I_F = 2.4\text{A}, di/dt = 100\text{A}/\mu\text{s}$
Q_{rr}	Reverse Recovery Charge	N-Ch	—	56	84	nC	P-Channel
		P-Ch	—	66	99		$T_J = 25^\circ\text{C}, I_F = -1.8\text{A}, di/dt = -100\text{A}/\mu\text{s}$ ③

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 10)
- ② N-Channel $I_{SD} \leq 2.4\text{A}$, $di/dt \leq 73\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 150^\circ\text{C}$
P-Channel $I_{SD} \leq -1.8\text{A}$, $di/dt \leq 90\text{A}/\mu\text{s}$, $V_{DD} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 150^\circ\text{C}$
- ③ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.
- ④ Surface mounted on FR-4 board, $t \leq 10\text{sec}$.

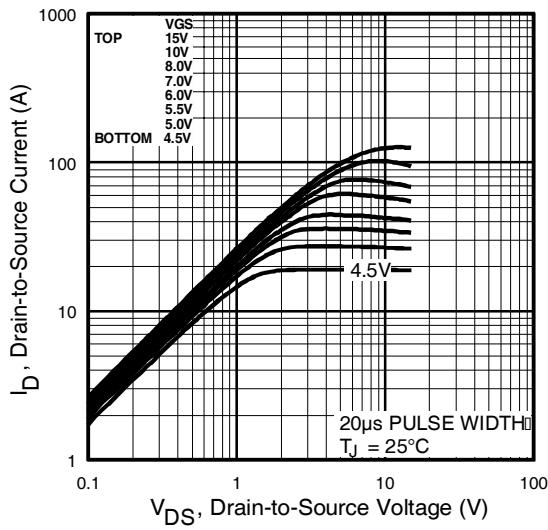


Fig 1. Typical Output Characteristics

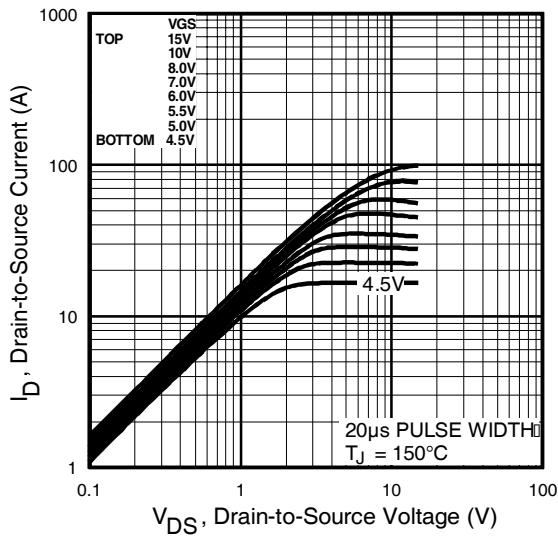


Fig 2. Typical Output Characteristics

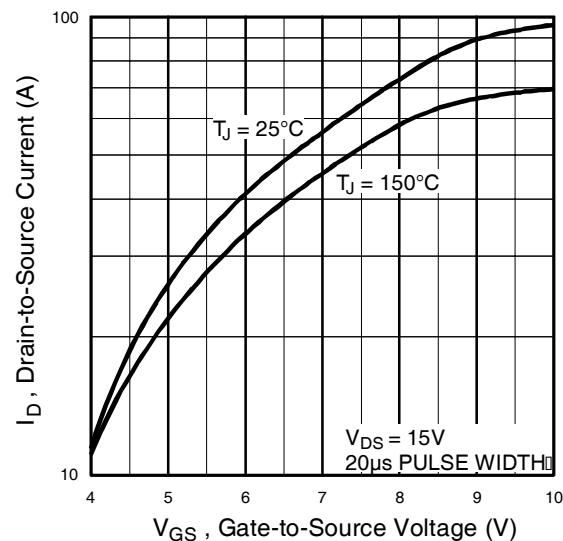


Fig 3. Typical Transfer Characteristics

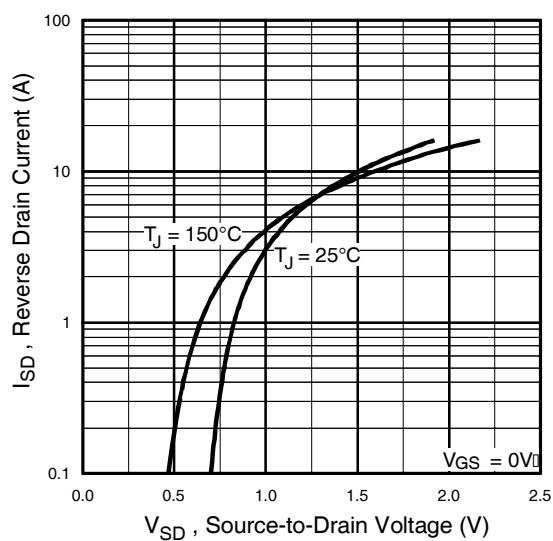


Fig 4. Typical Source-Drain Diode Forward Voltage

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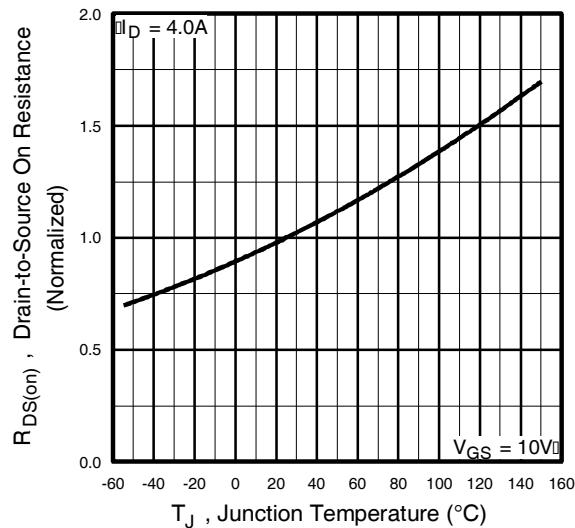


Fig 5. Normalized On-Resistance Vs. Temperature

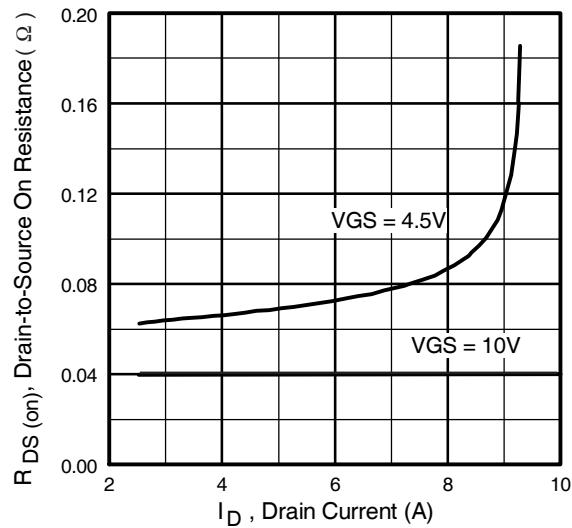


Fig 6. Typical On-Resistance Vs. Drain Current

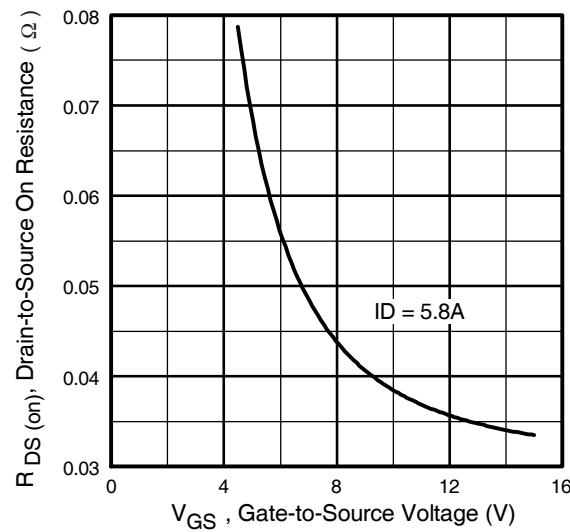


Fig 7. Typical On-Resistance Vs. Gate Voltage

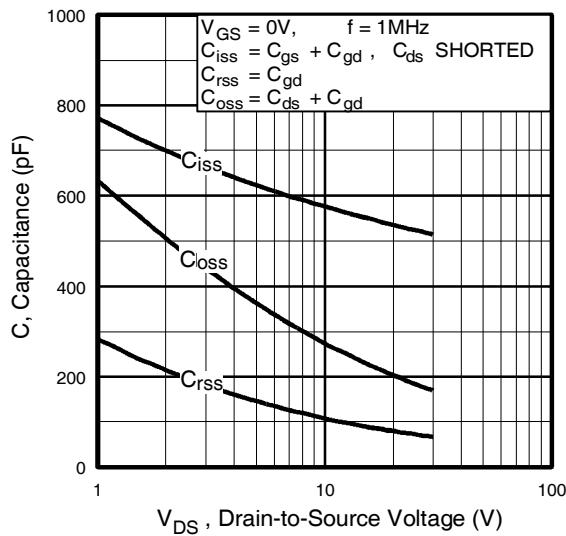


Fig 8. Typical Capacitance Vs.
Drain-to-Source Voltage

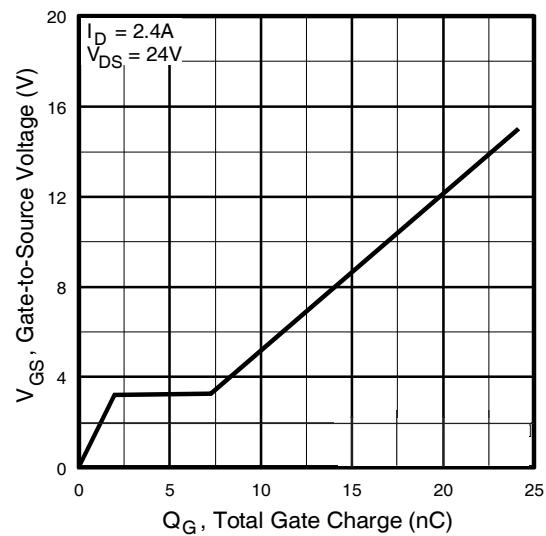


Fig 9. Typical Gate Charge Vs.
Gate-to-Source Voltage

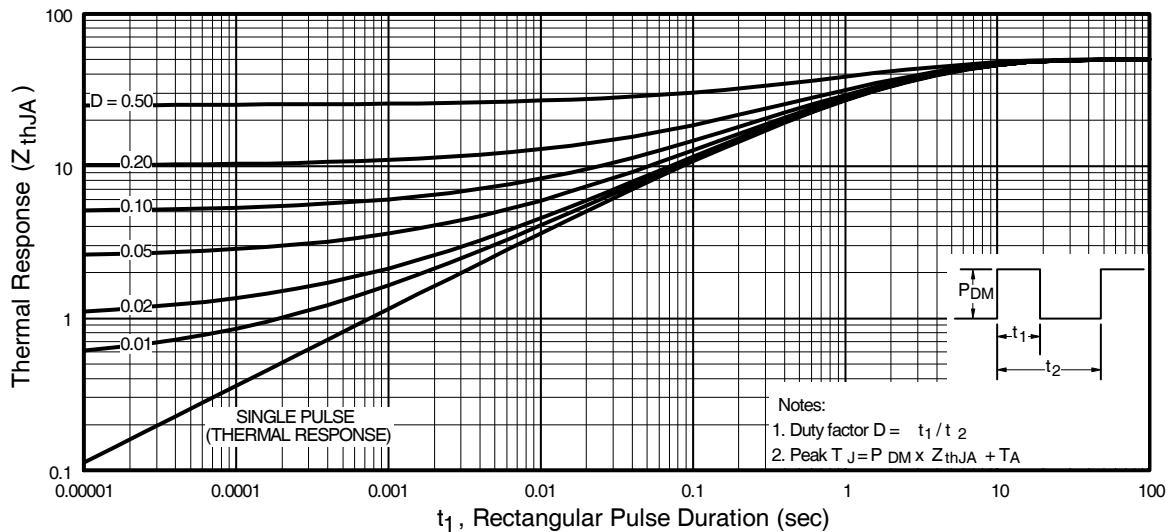


Fig 10. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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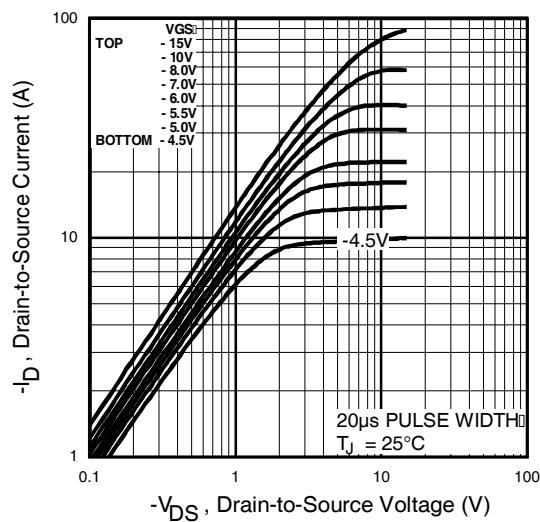


Fig 11. Typical Output Characteristics

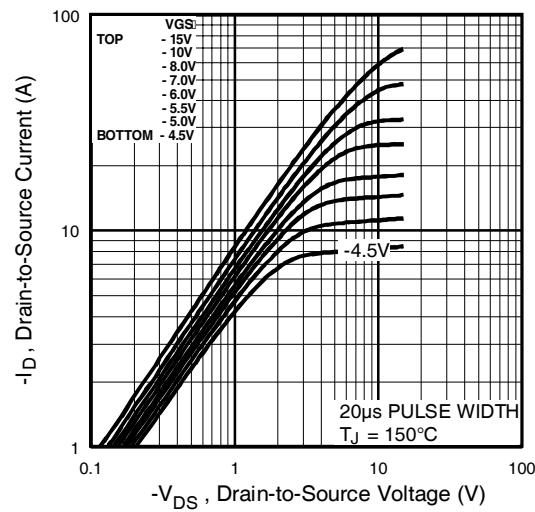


Fig 12. Typical Output Characteristics

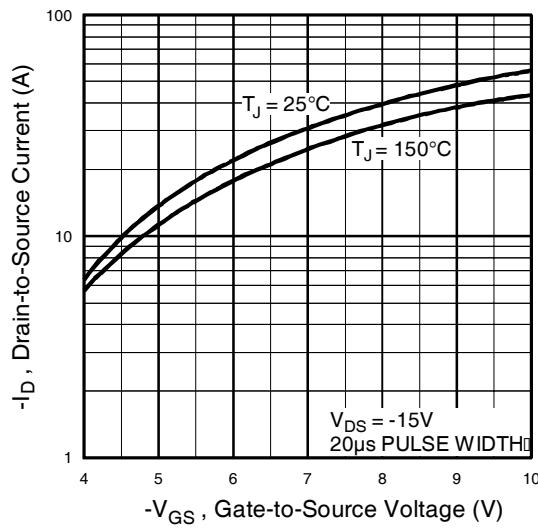


Fig 13. Typical Transfer Characteristics

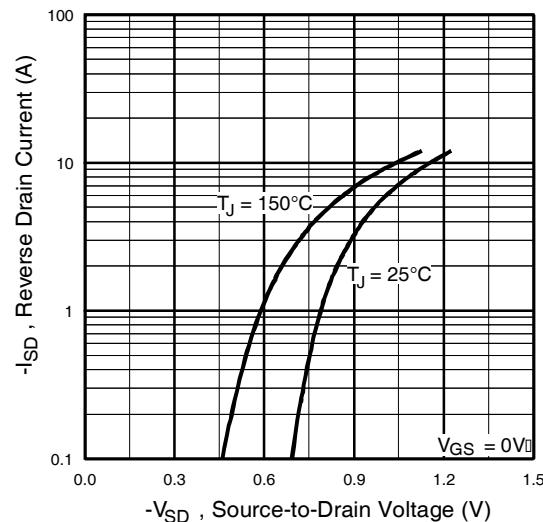


Fig 14. Typical Source-Drain Diode Forward Voltage

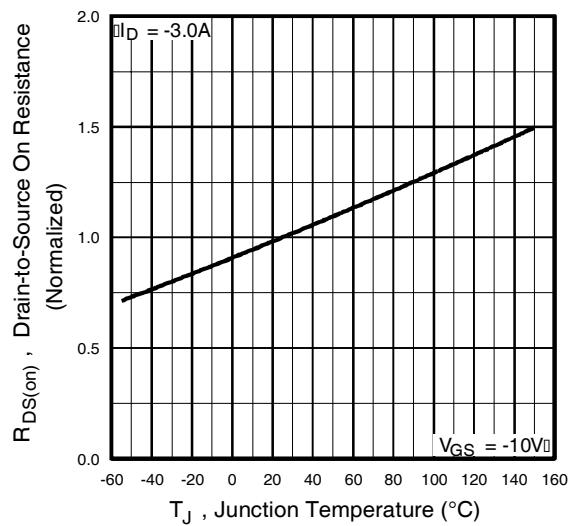


Fig 15. Normalized On-Resistance Vs. Temperature

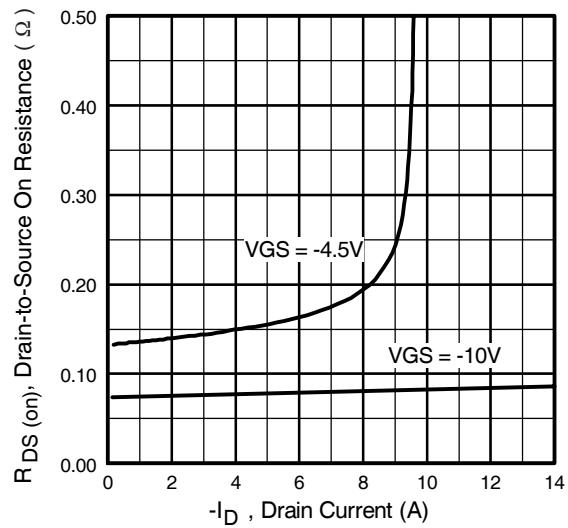


Fig 16. Typical On-Resistance Vs. Drain Current

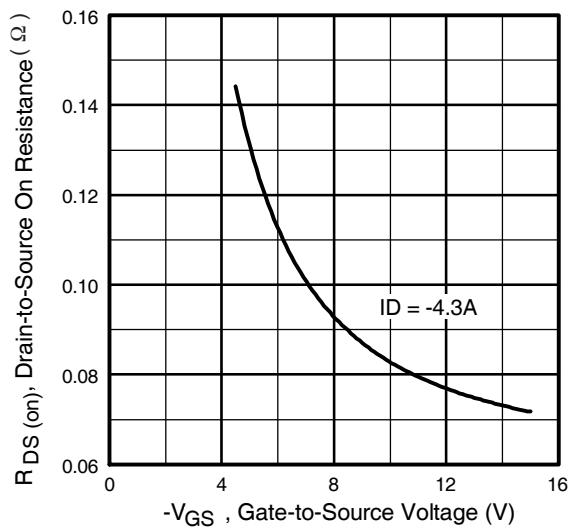


Fig 17. Typical On-Resistance Vs. Gate Voltage

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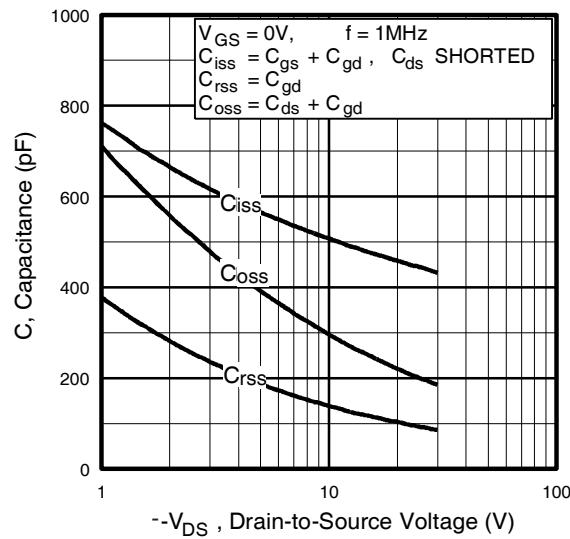


Fig 18. Typical Capacitance Vs.
Drain-to-Source Voltage

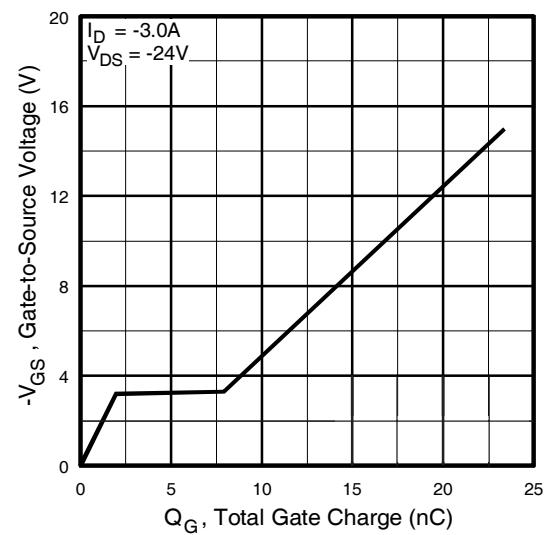


Fig 19. Typical Gate Charge Vs.
Gate-to-Source Voltage

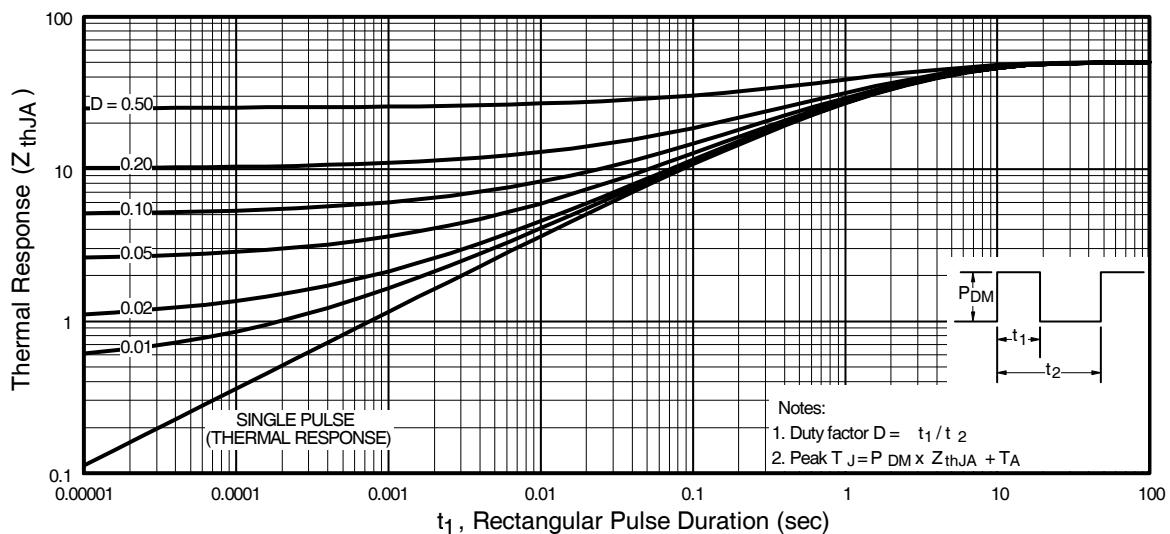


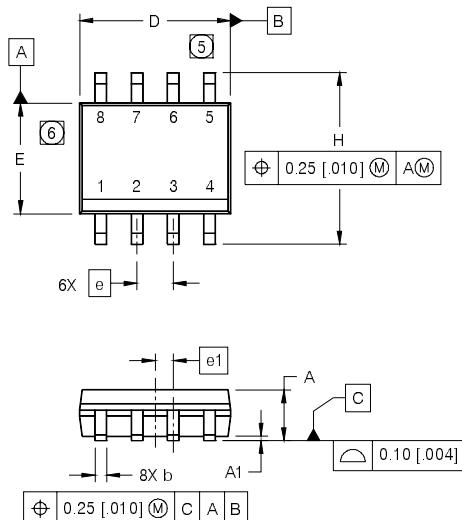
Fig 20. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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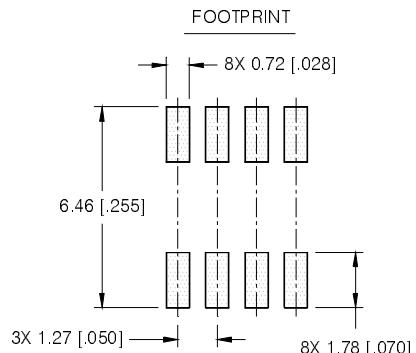
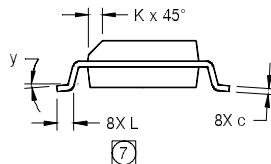
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SO-8 Package Outline

Dimensions are shown in millimeters (inches)



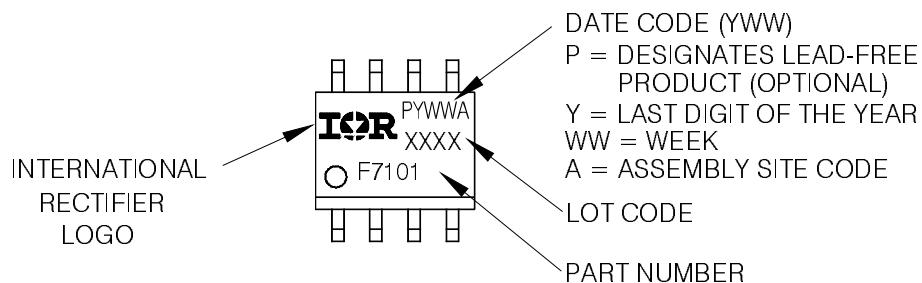
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050	BASIC	1.27	BASIC
e1	.025	BASIC	0.635	BASIC
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°



- NOTES:
1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
 2. CONTROLLING DIMENSION: MILLIMETER
 3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
 - 5) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 [.006].
 - 6) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 [.010].
 - 7) DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.

SO-8 Part Marking

EXAMPLE: THIS IS AN IRF7101 (MOSFET)



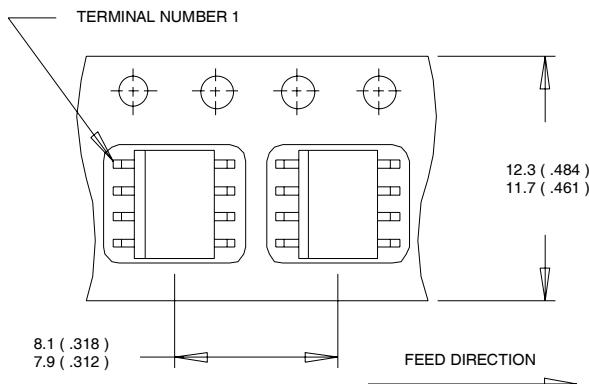
Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>
www.irf.com

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SO-8 Tape and Reel

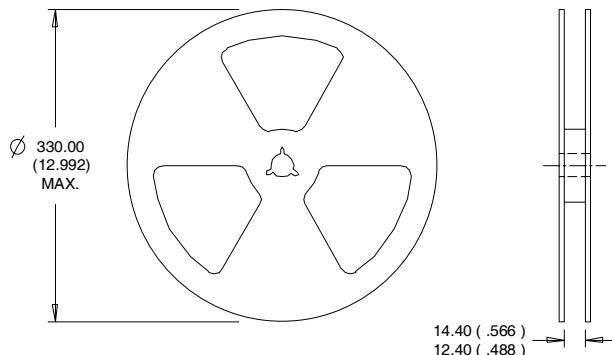
Dimensions are shown in millimeters (inches)

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NOTES:

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

Data and specifications subject to change without notice.
This product has been designed and qualified for the Automotive [Q101] market.
Qualification Standards can be found on IR's Web site.

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